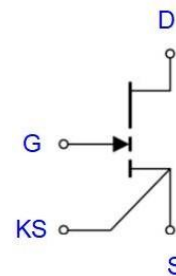


Description

SGN65N130DN is an enhancement mode GaN-on-silicon transistor. GaN is a wide band gap semiconductor with high power density. The gallium nitride transistor is characterized by no body diode, so the reverse recovery charge is zero.

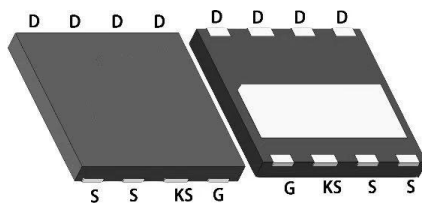
Features

- 650 V enhancement mode power switch
- $R_{DS(on)} = 130m\Omega$
- $I_{DS(max)} = 15A$
- Easy gate drive requirements (0 V to 6 V)
- Very high switching frequency (> 10 MHz)
- Fast and controllable fall and rise times
- Zero reverse recovery loss

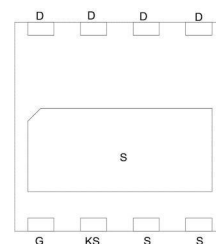


Device Information

Part Number	Marking Code	Package	Packing
SGN65N130DN	SGN65N130	DFN8x8	260pcs/tray



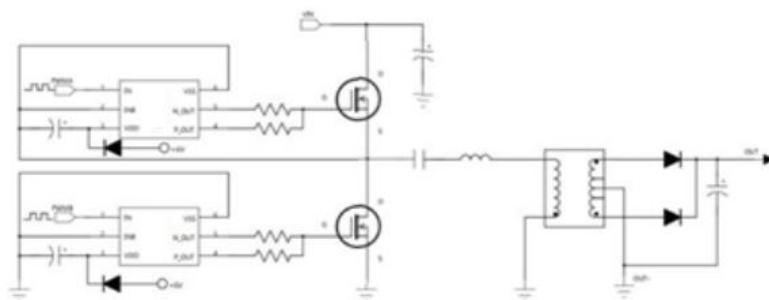
SGN65N130DN DFN8x8



SGN65N130DN Bottom View

Applications

- Fast Battery Charging
- LED lighting drivers
- Power Factor Correction
- LLC Converters
- Wireless Power Transfer



Typical application circuit for LL

Absolute Maximum Ratings (Tc=25°C unless otherwise specified)

Parameter	Symbol	Value	Unit	Condition
Drain-Source voltage	V_{DS}	650	V	
Gate-source voltage	V_{GS}	-7 to 6	V	
Continuous drain current*	I_D	18	A	Tc=25°C
		14	A	Tc=125°C
Operation and storage temperature	T_j	-55 to 150	°C	
	T_{stg}	-55 to 150	°C	

* An Estimated Value

Thermal characteristics

Parameter	Symbol	Values	Unit	Note/Test Condition
Thermal resistance, junction-ambient	R _{thJA}	60.3	°C/W	
Thermal resistance, junction-case	R _{thJC}	1.1	°C/W	
Maximum reflow soldering temperature	T _{sold}	260	°C	MSL3

Electrical Characteristics (T_c=25 °C unless otherwise specified)

Typical Performance – Static

Parameter	Symbol	Values			Unit	Test condition
		Min.	Type.	Max.		
Drain source breakdown voltage	BVDS	650	/	/	V	VGS=0V, ID=20μA
Total drain leakage current	IDSS	/	0.7	25	μA	VDS=650V, VGS=0V, Tj=25 °C
		/	6	200	μA	VDS=650V, VGS=0V, Tj=150 °C
Gate-to-source current	IGSS	/	66	/	μA	VDS=0V, VGS=6V, Tj=25 °C
Static drain-source on-resistance	RDS(ON)	/	104	130	mΩ	VGS=6V, ID=3A, Tj=25 °C
		/	215	/	mΩ	VGS=6V, ID=3A, Tj=150 °C
Gate threshold voltage	VGS(th)	1.2	1.6	2.0	V	VDS=VGS, ID=3.5mA,

**Typical Performance – Dynamic**

Parameter	Symbol	Values			Unit	Test condition
		Min	Type	Max		
Input capacitance	C_{ISS}	/	119	/	pF	$V_{DS}=400V$, $V_{GS}=0V$, $f=1MHz$
Output capacitance	C_{OSS}	/	39	/	pF	
Reverse transfer Capacitance	C_{RSS}	/	0.3	/	pF	
Output capacitance, energy Related	$C_{OSS(er)}$	/	48	/	pF	$V_{DS}=0V$ to $400V, V_{GS}=0V$
Output capacitance time related	$C_{OSS(tr)}$	/	78	/	pF	
Total gate charge	Q_G	/	3.7	/	nC	$V_{DS}=400V$, $V_{GS}=0V$ to $6V$
Gate-drain charge	Q_{GD}	/	1.4	/	nC	
Gate-source charge	Q_{GS}	/	0.2	/	nC	
Gate Resistance	R_G	/	3.3	/	Ω	$f = f_{res}$, Open drain

Characteristic Curve

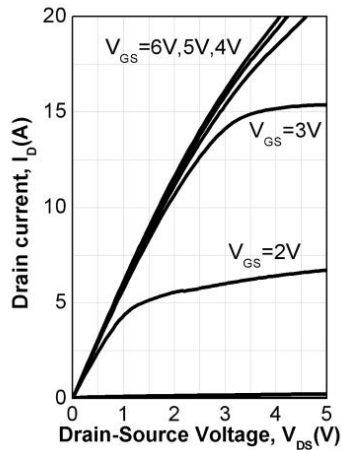


Fig.1 Typical output characteristics @ $T_j = 25^\circ\text{C}$

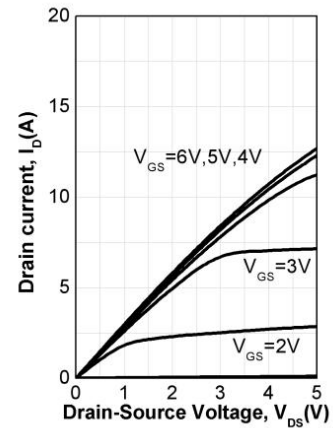


Fig.2 Typical output characteristics @ $T_j = 150^\circ\text{C}$

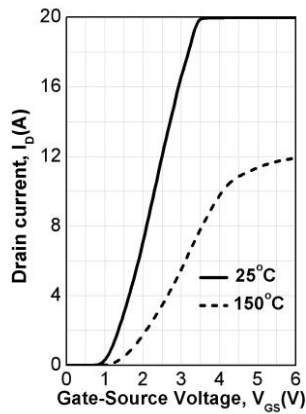


Fig.3 Typical transfer characteristics @ $V_{DS} = 5V$

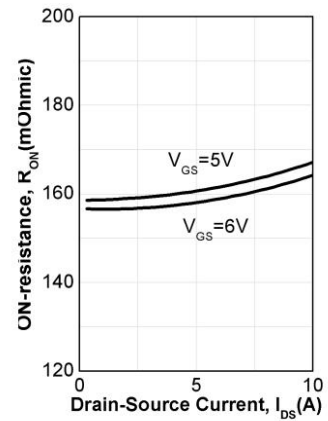


Fig.4 ON-resistance for various drain current @ 25°C

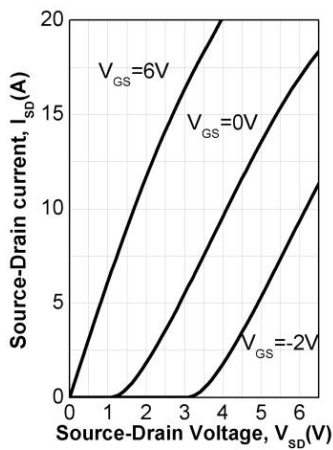


Fig.5 Typical reverse conduction characteristics

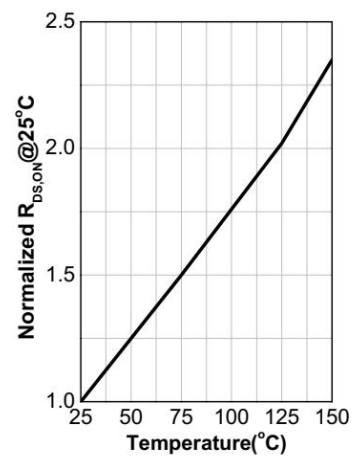


Fig.6 Normalized ON-resistance at various temperatures

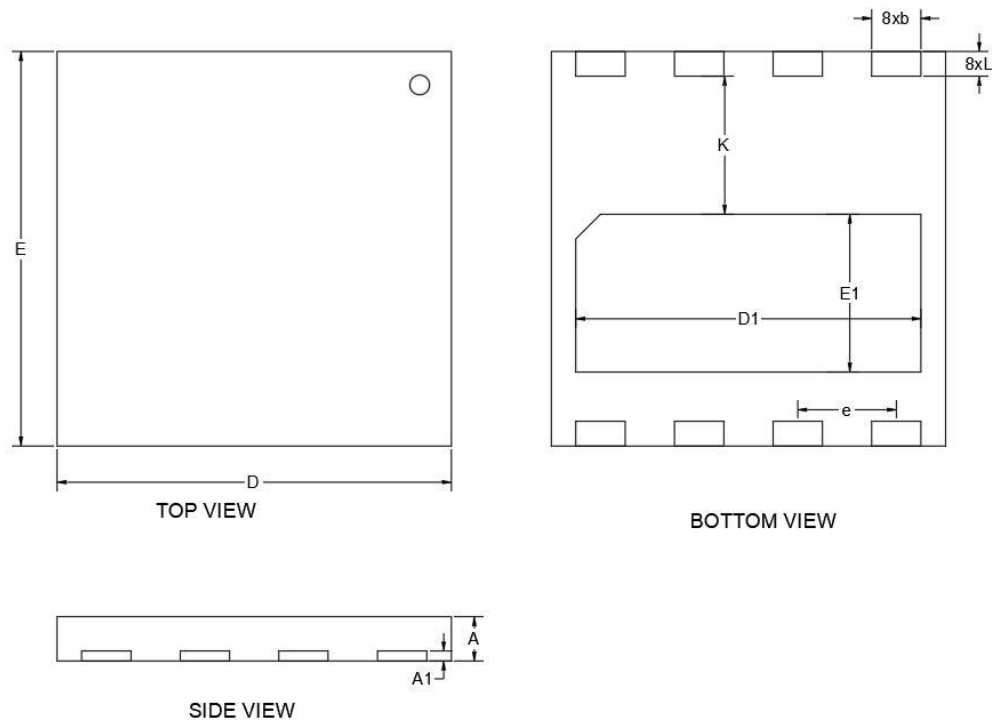


SGN65N130DN

E-mode GaN-on-Silicon FET

Package

Dimensions(mm)			
Symbol	Min.	Nom.	Max.
A	0.80	0.90	1.00
A1	REF 0.203		
B	0.95	1.00	1.05
D	7.90	8.00	8.10
D1	6.90	7.00	7.10
E	7.90	8.00	8.10
E1	3.10	3.20	3.30
E	REF 2.00		
K	REF 2.80		
L	0.45	0.50	0.55





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